

ABSTRACT OF THE DISCLOSURE

A method of checking for errors in line width in an integrated circuit includes identifying with a marker any lines having a line width greater than a default minimum line width, and associating a line width parameter with each line width marker, the line width parameter corresponding to a line width for the marked line. The line width parameters and line width markers are converted to lines in a layout, and the line width parameters for each line width marker are compared to the actual layout line width.